



HEIWA.017AUS

PATENT

2829/1075
grace
\$

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Hideyuki Oshima) Group Art Unit 2829
Serial No. : 10/507,042)
Filed : September 7, 2004)
For : SEMICONDUCTOR TEST)
APPARATUS FOR TESTING)
SEMICONDUCTOR DEVICE THAT)
PRODUCES OUTPUT DATA BY)
ITS INTERNAL CLOCK TIMING)
Examiner : Minh N. Tang)

AMENDMENT

Hon. Commissioner
of Patents and Trademarks
Alexandria, VA 22313-1450

Dear Sir:

This amendment is submitted for the above-identified patent application in response to the office action from the United States Patent and Trademark Office mailed August 8, 2005. Please make the following changes.